Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
10/782,816	KOMURO ET AL.	
Examiner	Art Unit	
Sonhia S. Chen	2852	

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SEARCHED					
Class	Subclass	Date	Examiner		
399	328, 320, 333	12/6/2005	sc		
347	156	12/6/2005	sc		
above	updated	3/8/2006	sc		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
399/329; 219/216,388,243,469; 430/124,97 (text search - see search history printout)	12/6/2005 (Updated on 3/8/06	sc (SC)		
EAST (USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See search history printout	12/6/2005 (updated or 3/8/06	sc (Sc)		
EAST (EPO, JPO) - See search history printout	12/6/2005	sc		